Finding one of *D* defective elements in the additive group testing model

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Additive Group Testing Model

- $[N] := \{1, 2, \dots, N\}$ set of elements
- $\mathcal{D} \subset [N]$ a set of defective elements with $D = |\mathcal{D}|$.

•
$$[i,j] := \{x \in \mathcal{N} : i \le x \le j\}$$

• 2^[N] the set of all subsets of [N].

The aim of a searcher is to determine a goal set $\mathcal{G} \subset [N]$. (for example in classical group testing with $\mathcal{G} = \mathcal{D}$.) The searcher can choose sets (questions) $S_i \subset [N]$ and asks for the values $t(S_i)$ (answers) of a test function $t : 2^{[N]} \to \mathcal{R}$.

Definition

Let *t* be a test function, $s = (S_1, S_2, ..., S_n)$ be a sequence of sets $S_i \subset [N]$, and $t(s) := (t(S_1), ..., t(S_n))$. We call (s, t(s), n) a test with test length *n*, if the searcher uniquely determine \mathcal{G} .

Classical group testing

$$t^{(Cla)}(S) = \begin{cases} 0 & , \text{ if } |S \cap D| = 0 \\ 1 & , \text{ otherwise.} \end{cases}$$

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(2)

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Additive group testing

$$\mathsf{t}^{(\mathsf{Add})}(\mathcal{S}) = |\mathcal{S} \cap \mathcal{D}|$$

(1)

(2)

(3)

We distinguish between adaptive and nonadaptive tests.

- We call a test nonadaptive if all questions are specified simultaneously.
- A test is called adaptive if all questions are conducted one by one, and outcomes (t(S₁),...,t(S_{i-1})) of previous questions are known at the time of determining the current question S_i.

We consider only adaptive tests.

Problem 1

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Problem 2

Let us fix some $j \in [1, d]$ and call a test successfull if for any \mathcal{D} we have $G = \{d_j\}$, where $\mathcal{D} = \{d_1, \ldots, d_D\} \subset [N]$ and $d_1 < d_2, \cdots < d_D$. We assume again that D and n are given. How big can we choose N in this case to ensure a successful test? Denote by $N_{(Thr)}(n, D, u, m)$ the maximal number of elements in a set \mathcal{N} such that the searcher can find *m* defective elements in $\mathcal{D} \subset \mathcal{N}$ with the test function $t_{(Thr)}$ and test length *n*. In 2012 Ahlswede/Deppe/Lebedev proved the following

Theorem

If
$$D \ge u$$
 then $N_{(Thr)}(n, D, u, 1) = 2^n + D - 1$.

Denote by $N_{(Add)}(n, D)$ the maximal number of elements such that the searcher can find one defective element (construct a successfull test for the Problem 1) with test length *n*.

Theorem

We have $N_{(Add)}(n, D) = 2^n + D - 1$.

Denote by $N_{(Add)}(n, D, j)$ the maximal number of elements such that the searcher can find the *j*th defective element (construct a successfull test for the Problem 2) with test length *n*.

Theorem

We have $N_{(Add)}(n, D, j) = 2^n + D - 1$ for $1 \le j \le D$.

The searcher knows:

- One defective is in $[1, 2^{r-1} + 1]$
- One defective is in $[2^{r-1} + 2, 2^r + 2]$ for any fixed natural *r*.

The searcher needs at least *r* questions for finding one defective.

Example

Denote $T_0 = [1, 2^{r-1} + 1]$, $T_1 = [2^{r-1} + 2, 2^r + 2]$ and consider arbitrary question *S*, $S \subseteq [1, 2^r + 2]$. We have

$$T_{01} = S \bigcap T_0, \ T_{00} = T_0 \setminus T_{01}, \ T_{11} = S \bigcap T_1, \ T_{10} = T_1 \setminus T_{11}.$$

We assume that a genius gives the searcher the information how many defectives are in the sets T_{01} , T_{00} , T_{11} , T_{10} . We set

$$A = \begin{cases} T_{00} & , \text{ if } |T_{01}| \le |T_{00}| \\ T_{01} & , \text{ if } |T_{00}| < |T_{01}|. \end{cases}$$

and

$$B = \left\{ \begin{array}{ll} T_{10} & , \ \mathrm{if} \ |T_{11}| \leq |T_{10}| \\ T_{11} & , \ \mathrm{if} \ |T_{10}| < |T_{11}|. \end{array} \right.$$

For any question *S* it is possible to get an answer, such that there is one defective in the set *A* and there is one defective in the set *B*. Therefore $|A| \ge 2^{r-2} + 1$ and $|B| \ge 2^{r-2} + 1$. Thus by induction the assumption in the example is correct.

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